PATENT ABSTRACTS OF JAPAN

(11)Publication number:

2000-251496

(43)Date of publication of application: 14.09.2000

(51)Int.CI.

G11C 29/00 G01R 31/28 G11C 11/401 H01L 27/04 H01L 21/822

(21)Application number: 11-044549

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HITACHI ULSI SYSTEMS CO LTD

(22)Date of filing:

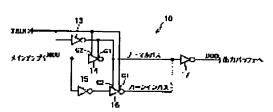
23.02.1999

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(54) SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE (57) Abstract:

PROBLEM TO BE SOLVED: To perform discrimination when a vender test mode is set surely without usinf a measuring device such as an ammeter and the like. SOLUTION: When a vender test mode in which a burn-in test is performed is set, a test input signal TBIN of a Hi level is outputted to a normal/burn-in signal output circuit 10 from a test control circuit, an inverter 13 is made a floating state, and an inverter 16 is operated. Therefore, data MO0 outputted from a sense amplifier is outputted to an output buffer as reversed data of data written through inverters 15–17. This reversed data are monitored by a burn-in tester, and it is discriminated that a burn-in test mode is set.



LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision